

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/789,042	AHN ET AL.	
Examiner	Art Unit	
Matthew C. Landau	2815	

SEARCHED					
Class	Subclass	Date	Examiner		
257	.132, .165, E39. 165, chi	8/28/07	^		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST Search (printout included)	8/28/07	~		